## Applicant(s)/Patent Under Application/Control No. Reexamination 10/628,058 LEE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Huyen X. Vo 2626 **U.S. PATENT DOCUMENTS Document Number** Date Country Code-Number-Kind Code Name Classification MM-YYYY \* Α US-6,804,639 10-2004 Ehara, Hiroyuki 704/223 US-6,199,035 03-2001 В Lakaniemi et al. 704/207 US-6,415,252 С 07-2002 Peng et al. 704/208 US-D US-Ε F US-G US-US-Н US-US-J US-Κ US-L US-FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

W

Х